# Schedule of Scope to Certificate of Approval

## Independent Testing Laboratory

### IECQ Certificate No.: IECQ-L DEKRA 16.0002-05

### CB Certificate No.: DEKRA-T5F-003

**Schedule Number: IECQ-L DEKRA 16.0002-05-S** **Rev No.:** 1 **Revision Date:** 2025/08/14 **Page** 1 **of** 1

## Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

| Description test | Standard |
|---|---|
| High Temperature Operation test (HTOL) | JESD22-A108, AEC-Q100, AEC-Q200, MIL-STD-202 |
| Low Temperature Operating Life (LTOL) | JESD22-A108 |
| High Temperature Forward Bias (HTFB) | JESD22-A108 |
| High Temperature Gate Bias (HTGB) | JESD22-A108, AEC-Q101 |
| High Temperature Reverse Bias (HTRB) | JESD22-A108, AEC-Q101, MIL-STD-750, MIL-STD-883 |
| Early Life Failure Rate (ELFR) | JESD22-A108, AEC-Q100 |
| Highly Acclerated Stress Test (HAST) | JESD22-A110, AEC-Q100, AEC-Q101 |
| Steady-Status Temperature and Humidity Bias Life Test (THB) | JESD22-A101, AEC-Q100, AEC-Q101, AEC-Q200, MIL-STD-202 |
| Power and Temperature Cycling (PTC) | JESD22-A105, AEC-Q100, AEC-Q101 |
| Electromigration (EM) | JEP001, JESD61, JESD87, AEC-Q100, |
| Stress Migration (SM) | JEP001, JEP139, JESD87, AEC-Q100, |
| Steady-Status operation life | MIL-STD-750, MIL-STD-883 |
| Solderability test | J-STD-020, JESD22-B102 |